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| APPLICATION NO. | FILING DATE | FIRST NAMED INVENTOR | ATTORNEY DOCKET NO. | CONFIRMATION NO. |
|-----------------|-------------|----------------------|---------------------|------------------|
| 10/696,759      | 10/29/2003  | Fang-Zhong Chen      | 15436.247.5.1       | 7926             |

22913 7590 04/15/2005

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EXAMINER

NGUYEN, JIMMY

| ART UNIT | PAPER NUMBER |
|----------|--------------|
|----------|--------------|

2829

DATE MAILED: 04/15/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

|                              |                               |                            |  |
|------------------------------|-------------------------------|----------------------------|--|
| <b>Office Action Summary</b> | Application No.<br>10/696,759 | Applicant(s)<br>CHEN ET AL |  |
|                              | Examiner<br>Jimmy Nguyen      | Art Unit<br>2829           |  |

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --  
**Period for Reply**

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

#### Status

- 1) ☒ Responsive to communication(s) filed on 24 January 2005.
- 2a) ☐ This action is **FINAL**.                      2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

#### Disposition of Claims

- 4) ☒ Claim(s) 1-24 is/are pending in the application.
- 4a) Of the above claim(s) \_\_\_\_\_ is/are withdrawn from consideration.
- 5) ☐ Claim(s) \_\_\_\_\_ is/are allowed.
- 6) ☒ Claim(s) 1-24 is/are rejected.
- 7) ☐ Claim(s) \_\_\_\_\_ is/are objected to.
- 8) ☐ Claim(s) \_\_\_\_\_ are subject to restriction and/or election requirement.

#### Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☒ The drawing(s) filed on 10/29/03 is/are: a) ☒ accepted or b) ☐ objected to by the Examiner.  
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).  
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

#### Priority under 35 U.S.C. § 119

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All    b) ☐ Some \* c) ☐ None of:
1. ☐ Certified copies of the priority documents have been received.
  2. ☐ Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.
  3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

\* See the attached detailed Office action for a list of the certified copies not received.

#### Attachment(s)

- |  |   |
|--|---|
| 1) <input checked="" type="checkbox"/> Notice of References Cited (PTO-892)  | 4) <input type="checkbox"/> Interview Summary (PTO-413)<br>Paper No(s)/Mail Date. _____ |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948)                                   | 5) <input type="checkbox"/> Notice of Informal Patent Application (PTO-152)             |
| 3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)<br>Paper No(s)/Mail Date _____ | 6) <input type="checkbox"/> Other: _____  |

## **DETAILED ACTION**

### **Response to Argument**

The examiner acknowledges the amendment filed 1/24/05 persuasive, however upon further search, the examiner makes new ground of rejection.

### ***Claim Rejections - 35 USC § 102***

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

2. Claims 1 - 24 are rejected under 35 U.S.C. 102(b) as being anticipated by Browning et al (US 6,229,325).

**As to claim 1**, Browning et al disclose (figs 1- 3) a system for testing optoelectronic devices, the system comprising:

a burn-in rack (3) mountable within a support structure (6), said burn-in rack (3) supports a plurality of optoelectronic devices (display devices lay within holder 20, fig 2) during burn-in testing and life testing, said burn in rack (3) with said plurality of optoelectronic devices (display devices) being disposable in either a burn-in oven (9) or within said support structure (3) for life testing, and

a detector assembly (62, fig 4) mounted to said support structure, said detector assembly comprising a plurality of detectors (62), each of said plurality of detectors (62) aligning with one of said plurality of optoelectronic devices (display devices) to detect an

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output of each of said plurality of optoelectronic devices (display devices) during the testing.

**As to claim 2**, Browning et al disclose (figs 1- 3) a system as recited in claim 1, wherein system further comprising a computer (1,2,4) in electrical communication with at least one of burn in rack (3) and detector assembly (62).

**As to claim 3**, Browning et al disclose (figs 1- 3) a system as recited in claim 2, wherein computer (1,24) controls life testing and burn in testing.

**As to claims 4, 7, 14**, Browning et al disclose (fig 2) a system as recited in claim 1, wherein burn in rack comprises:

A rack base (3) that supports a circuit board; and

At least one diode support (20) disposed from and supported by rack base, at least one diode support supporting plurality of optoelectronic devices (display devices).

**As to claims 5, 8**, Browning et al disclose (figs 1- 3) a system as recited in claim 1, wherein plurality of detectors (46) are organized in an array.

**As to claims 6, 12, 13, 20,** Browning disclose (fig 2) a system and a method for testing optoelectronic devices, the system and method comprising:

a burn-in rack (3) having a plurality of laser diode holders (20) and electrical signal connectors for electrically coupling laser diodes mounted in said holders (20) to a first electrical connector,

a test apparatus (1, 2, 4) configured to hold said burn-in rack (3) and having optical detectors (62, fig 4) arranged to receive light from said laser diodes (display devices) mounted to said burn in rack (3) and couple output signals from said optical detectors (62) to a second electrical connector,

a computer (1,2,4) coupled to said first and second electrical connectors, said creating a drive current supplied to each laser diode ( display devices) and measuring the light output from said optical detectors (62).

**As to claim 9,** Browning disclose (fig 2) a system of claim 6, wherein electrical connectors are edge connectors (all the connectors are not shown, however every electrical wires have the connectors at the end).

**As to claim 10,** Browning disclose (fig 2) a system of claim 6, wherein burn in rack (3) slidably cooperates with test apparatus.

**As to claim 11**, Browning disclose (fig 2) a system of claim 6, wherein burn in rack (3) is capable of being disposed within a burn in oven (9).

**As to claim 15**, Browning disclose (fig 2) a system of claim 6, wherein burn in rack (3) further comprises at least circuit board (burn in board is the circuit board) electrically connected to a plurality of optoelectronic device holders (20) and plurality of optoelectronic devices (display devices) disposed within plurality of optoelectronic device holders (20).

**As to claim 16**, Browning disclose (fig 2) a system of claim 12, wherein means for detecting comprises a detector assembly (46) having a plurality of detectors (the combination of detector 62 and multiplexor 63 are represent for plurality of detectors).

**As to claim 17** Browning disclose (fig 2) a system of claim 16, wherein plurality of detectors (62, 63) detect electromagnetic waves propagated from plurality of optoelectronic devices (display devices).

**As to claims 18, 21**, Browning disclose (fig 2) a system of claim 12 and method of claim 20, wherein means for detecting comprises a monitor detector (62) integrated within each of plurality of optoelectronic devices (display devices).

**As to claim 19**, Browning disclose (fig 2) a system of claim 12. wherein means for delivering comprising a computer (1,2,4) electrically connected to plurality of optoelectronic devices (display devices) and means for detecting.

**As to claims 22 - 24**, Hashinaga et al disclose (figs 1- 3) the method further comprising step of calibrating integrated detector and optical detectors (by the computer 1,2,4) and removing burn in rack (3) and performing a burin process.

### ***Conclusion***

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Jimmy Nguyen whose telephone number is (703) 306-5858. The examiner can normally be reached on M-F from 9 to 5.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Ramteiz Nestor, can be reached on 571-272-2034. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should

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you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

JN.

April 11, 2005

  
**VINH NGUYEN**  
**PRIMARY EXAMINER**  
A-u.2829  
04/13/05